PSMN4R0-30YL



N-channel 30 V 4 m Ω logic level MOSFET in LFPAK Rev. 04 — 10 March 2011 Produc

Product data sheet

Product profile 1.

1.1 General description

Logic level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product is designed and qualified for use in industrial and communications applications.

1.2 Features and benefits

- High efficiency due to low switching and conduction losses
- Suitable for logic level gate drive sources

1.3 Applications

- Class-D amplifiers
- DC-to-DC converters

- Motor control
- Server power supplies

1.4 Quick reference data

Table 1. Quick reference data

Parameter	Conditions	Min	Тур	Max	Unit
drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C	-	-	30	V
drain current	T_{mb} = 25 °C; V_{GS} = 10 V; see <u>Figure 1</u>	-	-	100	Α
total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	-	69	W
junction temperature		-55	-	175	°C
acteristics					
drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A};$ $T_j = 25 \text{ °C}$	-	2.72	4	mΩ
naracteristics					
gate-drain charge	$V_{GS} = 4.5 \text{ V}; I_D = 10 \text{ A};$	-	4.3	-	nC
total gate charge	V _{DS} = 12 V; see <u>Figure 14;</u> see <u>Figure 15</u>	-	17.6	-	nC
Avalanche ruggedness					
non-repetitive drain-source avalanche energy	V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_D = 99 A; $V_{sup} \le$ 30 V; R_{GS} = 50 Ω ; unclamped	-	-	41	mJ
	drain-source voltage drain current total power dissipation junction temperature acteristics drain-source on-state resistance paracteristics gate-drain charge total gate charge ruggedness non-repetitive drain-source avalanche	drain-source voltage $T_j \ge 25 ^{\circ}\text{C}; T_j \le 175 ^{\circ}\text{C}$ drain current $T_{mb} = 25 ^{\circ}\text{C}; V_{GS} = 10 \text{V};$ see Figure 1 total power dissipation $T_{mb} = 25 ^{\circ}\text{C}; \text{see Figure 2}$ junction temperature deteristics drain-source on-state resistance $V_{GS} = 10 \text{V}; I_D = 15 \text{A};$ $T_j = 25 ^{\circ}\text{C}$ paracteristics gate-drain charge $V_{GS} = 4.5 \text{V}; I_D = 10 \text{A};$ $V_{DS} = 12 \text{V}; \text{see Figure 14};$ $V_{DS} = 12 \text{V}; \text{see Figure 14};$ $V_{DS} = 12 \text{V}; \text{see Figure 15}$ ruggedness non-repetitive $V_{GS} = 10 \text{V}; T_{j(\text{init})} = 25 ^{\circ}\text{C};$ $V_{DS} = 99 \text{A}; V_{sup} \le 30 \text{V};$	drain-source voltage $T_j \ge 25 ^{\circ}\text{C}; T_j \le 175 ^{\circ}\text{C}$ - drain current $T_{mb} = 25 ^{\circ}\text{C}; V_{GS} = 10 \text{V};$ - see Figure 1 total power dissipation $T_{mb} = 25 ^{\circ}\text{C}; \text{see Figure 2}$ - junction temperature -55 acteristics drain-source on-state resistance $V_{GS} = 10 \text{V}; I_D = 15 \text{A};$ - $T_j = 25 ^{\circ}\text{C}$ arracteristics gate-drain charge $V_{GS} = 4.5 \text{V}; I_D = 10 \text{A};$ - total gate charge $V_{GS} = 12 \text{V}; \text{see Figure 14};$ see Figure 15 ruggedness non-repetitive $V_{GS} = 10 \text{V}; T_{j(\text{init})} = 25 ^{\circ}\text{C};$ - In the source avalanche $V_{GS} = 10 \text{V}; T_{j(\text{init})} = 25 ^{\circ}\text{C};$ - In the source avalanche $V_{GS} = 10 \text{V}; T_{j(\text{init})} = 25 ^{\circ}\text{C};$ - In the source avalanche $V_{GS} = 10 \text{V}; T_{j(\text{init})} = 25 ^{\circ}\text{C};$ - In the source avalanche $V_{GS} = 10 \text{V}; T_{j(\text{init})} = 25 ^{\circ}\text{C};$ - In the source avalanche $V_{GS} = 10 \text{V}; T_{j(\text{init})} = 25 ^{\circ}\text{C};$ - $V_{GS} = 10 \text{V}; T_{j(\text{init})} = 25 ^{\circ}\text{C};$ - $V_{GS} = 10 \text{V}; T_{j(\text{init})} = 25 ^{\circ}\text{C};$ - $V_{GS} = 10 \text{V}; T_{j(\text{init})} = 25 ^{\circ}\text{C};$ - $V_{GS} = 10 \text{V}; T_{j(\text{init})} = 25 ^{\circ}\text{C};$ - $V_{GS} = 10 \text{V}; T_{j(\text{init})} = 25 ^{\circ}\text{C};$ - $V_{GS} = 10 \text{V}; T_{j(\text{init})} = 25 ^{\circ}\text{C};$ - $V_{GS} = 10 \text{V}; T_{j(\text{init})} = 25 ^{\circ}\text{C};$ - $V_{GS} = 10 \text{V}; T_{j(\text{init})} = 25 ^{\circ}\text{C};$ - $V_{GS} = 10 \text{V}; T_{j(\text{init})} = 25 ^{\circ}\text{C};$	$\begin{array}{llllllllllllllllllllllllllllllllllll$	drain-source voltage $T_j \ge 25 ^{\circ}\text{C}; T_j \le 175 ^{\circ}\text{C}$ 30 drain current $T_{mb} = 25 ^{\circ}\text{C}; V_{GS} = 10 \text{V};$ 100 see Figure 1 total power dissipation $T_{mb} = 25 ^{\circ}\text{C}; \text{see Figure 2}$ 69 junction temperature -55 - 175 exteristics drain-source on-state resistance $T_j = 25 ^{\circ}\text{C}$



2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S	source		
2	S	source	mb	D
3	S	source		
4	G	gate	9	
mb	D	mounting base; connected to drain	1 2 3 4	mbb076 S
			SOT669 (LFPAK)	

3. Ordering information

Table 3. Ordering information

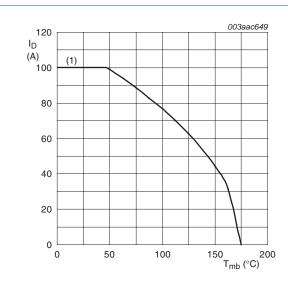
Type number	Package				
	Name	Description	Version		
PSMN4R0-30YL	LFPAK	plastic single-ended surface-mounted package (LFPAK); 4 leads	SOT669		

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C	-	30	V
V_{DSM}	peak drain-source voltage	$t_p \le 25 \text{ ns; } f \le 500 \text{ kHz; } E_{DS(AL)} \le 160 \text{ nJ;}$ pulsed	-	35	V
V_{DGR}	drain-gate voltage	$T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}; R_{GS} = 20 \text{ k}\Omega$	-	30	V
V_{GS}	gate-source voltage		-20	20	V
I _D	drain current	$V_{GS} = 10 \text{ V}; T_{mb} = 100 \text{ °C}; \text{ see } \frac{\text{Figure 1}}{\text{Model}}$	-	76	Α
		$V_{GS} = 10 \text{ V}; T_{mb} = 25 \text{ °C}; \text{ see } \frac{\text{Figure 1}}{\text{Model}}$	-	100	Α
I _{DM}	peak drain current	pulsed; $t_p \le 10 \mu s$; $T_{mb} = 25 ^{\circ}C$; see Figure 3	-	396	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	69	W
T _{stg}	storage temperature		-55	175	°C
Tj	junction temperature		-55	175	°C
Source-drai	n diode				
Is	source current	T _{mb} = 25 °C	-	99	Α
I _{SM}	peak source current	pulsed; $t_p \le 10 \mu s$; $T_{mb} = 25 ^{\circ}C$	-	396	Α
Avalanche r	ruggedness				
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_{D} = 99 A; V_{sup} ≤ 30 V; R_{GS} = 50 Ω ; unclamped	-	41	mJ



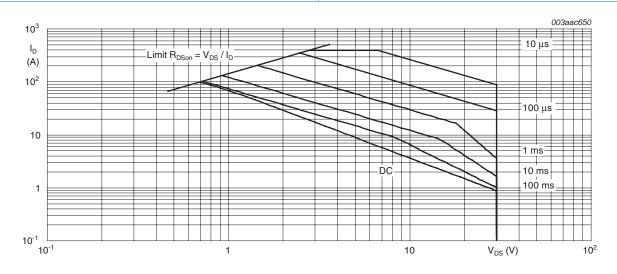
 $V_{GS} \ge 10 \text{V}$; (1) Capped at 100 A due to package.

120 P_{der} (%) 80 40 0 150 T_{mb} (°C)

 $P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100\%$

Continuous drain current as a function of Fig 1. mounting base temperature

Fig 2. Normalized total power dissipation as a function of mounting base temperature



 $T_{mb} = 25 \,^{\circ}C; I_{DM}$ is single pulse

Safe operating area; continuous and peak drain currents as a function of drain-source voltage

5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	see Figure 4	-	1	1.82	K/W

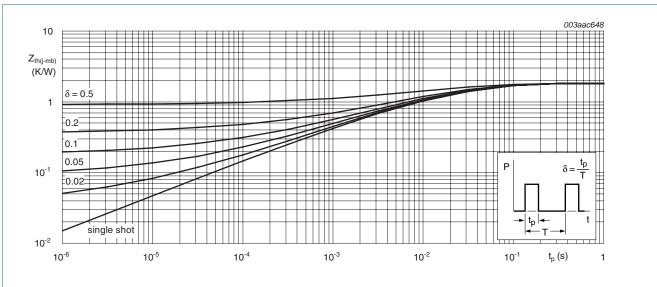


Fig 4. Transient thermal impedance from junction to mounting base as a function of pulse duration

6. Characteristics

Table 6. Characteristics

Tested to JEDEC standards where applicable.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static charac	cteristics					
V _{(BR)DSS}	drain-source breakdown	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = 25 °C$	30	-	-	V
	voltage	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = -55 °C$	27	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = 25$ °C; see <u>Figure 11</u> ; see <u>Figure 12</u>	1.3	1.7	2.15	V
		$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = 150$ °C; see Figure 12	0.65	-	-	V
		$I_D = 1 \text{ mA}$; $V_{DS} = V_{GS}$; $T_j = -55 \text{ °C}$; see Figure 12	-	-	2.45	V
I _{DSS}	drain leakage current	$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	1	μΑ
		$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 150 ^{\circ}\text{C}$	-	-	100	μΑ
I _{GSS}	gate leakage current	$V_{GS} = 16 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C}$	-	-	100	nA
		$V_{GS} = -16 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	100	nA
R _{DSon}	drain-source on-state	$V_{GS} = 4.5 \text{ V}; I_D = 15 \text{ A}; T_j = 25 ^{\circ}\text{C}$	-	3.73	5.25	mΩ
	resistance	$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A}; T_j = 150 \text{ °C};$ see <u>Figure 13</u>	-	-	7	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A}; T_j = 25 \text{ °C}$	-	2.72	4	mΩ
R_G	gate resistance	f = 1 MHz	-	0.52	1.5	Ω
Dynamic cha	aracteristics					
Q _{G(tot)}	total gate charge	$I_D = 10 \text{ A}$; $V_{DS} = 12 \text{ V}$; $V_{GS} = 10 \text{ V}$; see Figure 14; see Figure 15	-	36.6	-	nC
		$I_D = 10 \text{ A}$; $V_{DS} = 12 \text{ V}$; $V_{GS} = 4.5 \text{ V}$; see <u>Figure 14</u> ; see <u>Figure 15</u>	-	17.6	-	nC
		$I_D = 0 A$; $V_{DS} = 0 V$; $V_{GS} = 10 V$	-	33	-	nC
Q_{GS}	gate-source charge	$I_D = 10 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$	-	5.6	-	nC
Q _{GS(th)}	pre-threshold gate-source charge	see <u>Figure 14;</u> see <u>Figure 15</u>	-	3.6	-	nC
Q _{GS(th-pl)}	post-threshold gate-source charge		-	2	-	nC
Q_{GD}	gate-drain charge		-	4.3	-	nC
$V_{GS(pl)}$	gate-source plateau voltage	V _{DS} = 12 V; see <u>Figure 14</u> ; see <u>Figure 15</u>	-	2.3	-	V
C _{iss}	input capacitance	$V_{DS} = 12 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$	-	2090	-	pF
C _{oss}	output capacitance	T _j = 25 °C; see <u>Figure 16</u>	-	469	-	pF
C _{rss}	reverse transfer capacitance		-	227	-	pF
t _{d(on)}	turn-on delay time	V_{DS} = 12 V; R_L = 0.5 Ω ; V_{GS} = 4.5 V;	-	28	-	ns
t _r	rise time	$R_{G(ext)} = 4.7 \Omega$	-	51	-	ns
t _{d(off)}	turn-off delay time		-	44	-	ns
t _f	fall time		-	18	-	ns

 Table 6.
 Characteristics ...continued

Tested to JEDEC standards where applicable.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Source-drain diode						
V_{SD}	source-drain voltage	$I_S = 25 \text{ A}$; $V_{GS} = 0 \text{ V}$; $T_j = 25 \text{ °C}$; see Figure 17	-	0.83	1.2	V
t _{rr}	reverse recovery time	$I_S = 20 \text{ A}; dI_S/dt = -100 \text{ A/}\mu\text{s};$	-	39	-	ns
Q_r	recovered charge	$V_{GS} = 0 \text{ V}; V_{DS} = 20 \text{ V}$	-	36	-	nC

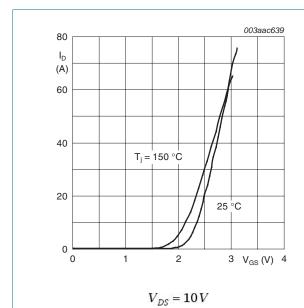
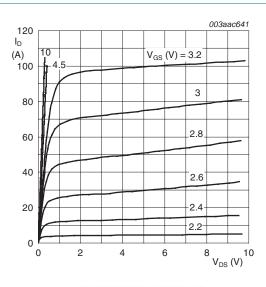


Fig 5. Transfer characteristics: drain current as a function of gate-source voltage; typical values



 $T_j = 25 \,^{\circ}C; t_p = 300 \,\mu s$

Fig 6. Output characteristics: drain current as a function of drain-source voltage; typical values

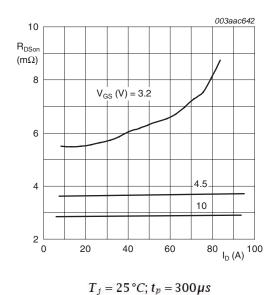
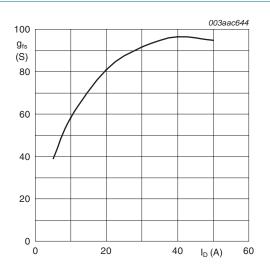


Fig 7. Drain-source on-state resistance as a function of drain current; typical values



 $T_j=25\,^{\circ}C; V_{DS}=15\,V$

Fig 8. Forward transconductance as a function of drain current; typical values

PSMN4R0-30YL

All information provided in this document is subject to legal disclaimers.

© NXP B.V. 2011. All rights reserved.

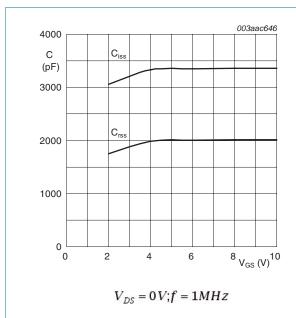


Fig 9. Input and reverse transfer capacitances as a function of gate-source voltage; typical values

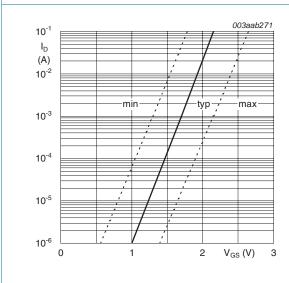
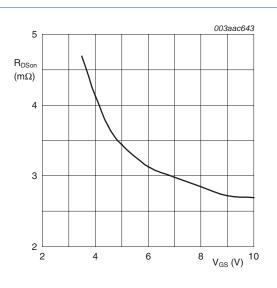


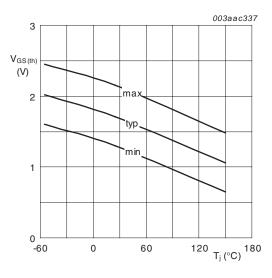
Fig 11. Sub-threshold drain current as a function of gate-source voltage

 $T_j = 25 \,^{\circ}C; V_{DS} = 5V$



 $T_j = 25 \,^{\circ}C; I_D = 15A$

Fig 10. Drain-source on-state resistance as a function of gate-source voltage; typical values



 $I_D = 1mA; V_{DS} = V_{GS}$

Fig 12. Gate-source threshold voltage as a function of junction temperature

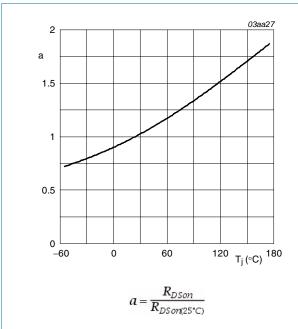
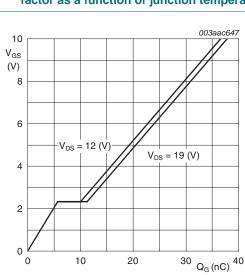


Fig 13. Normalized drain-source on-state resistance factor as a function of junction temperature



 $T_j = 25 \,^{\circ}C; I_D = 10A$

Fig 15. Gate-source voltage as a function of gate charge; typical values

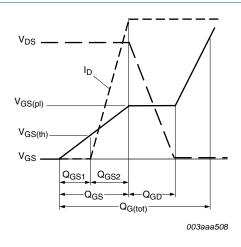
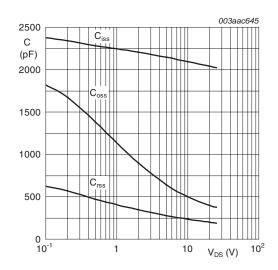


Fig 14. Gate charge waveform definitions



 $V_{GS} = 0V; f = 1MHz$

Fig 16. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

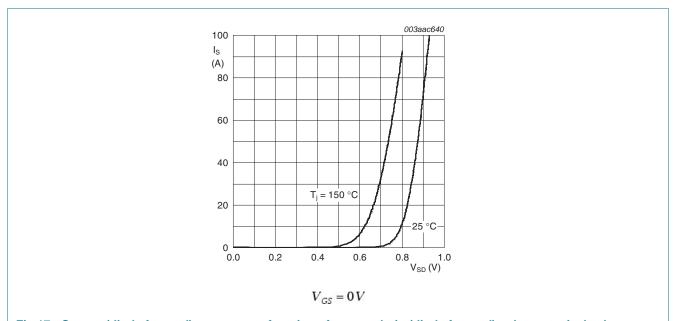


Fig 17. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values

Package outline



SOT669

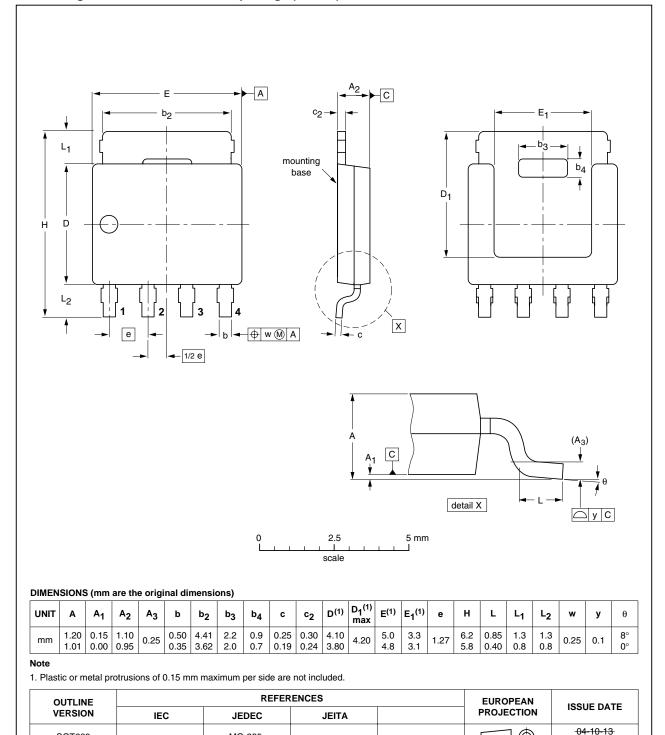


Fig 18. Package outline SOT669 (LFPAK)

PSMN4R0-30YL

All information provided in this document is subject to legal disclaimers.

© NXP B.V. 2011. All rights reserved.

06-03-16

MO-235

SOT669

Revision history

Table 7. **Revision history**

Document ID	Release date	Data sheet status	Change notice	Supersedes	
PSMN4R0-30YL v.4	20110310	Product data sheet	-	PSMN4R0-30YL v.3	
Modifications: • Various changes to content.					
PSMN4R0-30YL v.3	20091231	Product data sheet	-	PSMN4R0-30YL v.2	

9. Legal information

9.1 Data sheet status

Document status [1] [2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
- [3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL http://www.nxp.com.

9.2 Definitions

Draft — The document is a draft version only. The content is still under internal review and subject to formal approval, which may result in modifications or additions. NXP Semiconductors does not give any representations or warranties as to the accuracy or completeness of information included herein and shall have no liability for the consequences of use of such information.

Short data sheet — A short data sheet is an extract from a full data sheet with the same product type number(s) and title. A short data sheet is intended for quick reference only and should not be relied upon to contain detailed and full information. For detailed and full information see the relevant full data sheet, which is available on request via the local NXP Semiconductors sales office. In case of any inconsistency or conflict with the short data sheet, the full data sheet shall prevail.

Product specification — The information and data provided in a Product data sheet shall define the specification of the product as agreed between NXP Semiconductors and its customer, unless NXP Semiconductors and customer have explicitly agreed otherwise in writing. In no event however, shall an agreement be valid in which the NXP Semiconductors product is deemed to offer functions and qualities beyond those described in the Product data sheet.

9.3 Disclaimers

Limited warranty and liability — Information in this document is believed to be accurate and reliable. However, NXP Semiconductors does not give any representations or warranties, expressed or implied, as to the accuracy or completeness of such information and shall have no liability for the consequences of use of such information.

In no event shall NXP Semiconductors be liable for any indirect, incidental, punitive, special or consequential damages (including - without limitation - lost profits, lost savings, business interruption, costs related to the removal or replacement of any products or rework charges) whether or not such damages are based on tort (including negligence), warranty, breach of contract or any other legal theory.

Notwithstanding any damages that customer might incur for any reason whatsoever, NXP Semiconductors' aggregate and cumulative liability towards customer for the products described herein shall be limited in accordance with the *Terms and conditions of commercial sale* of NXP Semiconductors.

Right to make changes — NXP Semiconductors reserves the right to make changes to information published in this document, including without limitation specifications and product descriptions, at any time and without notice. This document supersedes and replaces all information supplied prior to the publication hereof.

Suitability for use — NXP Semiconductors products are not designed, authorized or warranted to be suitable for use in life support, life-critical or safety-critical systems or equipment, nor in applications where failure or malfunction of an NXP Semiconductors product can reasonably be expected to result in personal injury, death or severe property or environmental damage. NXP Semiconductors accepts no liability for inclusion and/or use of NXP Semiconductors products in such equipment or applications and therefore such inclusion and/or use is at the customer's own risk.

Quick reference data — The Quick reference data is an extract of the product data given in the Limiting values and Characteristics sections of this document, and as such is not complete, exhaustive or legally binding.

Applications — Applications that are described herein for any of these products are for illustrative purposes only. NXP Semiconductors makes no representation or warranty that such applications will be suitable for the specified use without further testing or modification.

Customers are responsible for the design and operation of their applications and products using NXP Semiconductors products, and NXP Semiconductors accepts no liability for any assistance with applications or customer product design. It is customer's sole responsibility to determine whether the NXP Semiconductors product is suitable and fit for the customer's applications and products planned, as well as for the planned application and use of customer's third party customer(s). Customers should provide appropriate design and operating safeguards to minimize the risks associated with their applications and products.

NXP Semiconductors does not accept any liability related to any default, damage, costs or problem which is based on any weakness or default in the customer's applications or products, or the application or use by customer's third party customer(s). Customer is responsible for doing all necessary testing for the customer's applications and products using NXP Semiconductors products in order to avoid a default of the applications and the products or of the application or use by customer's third party customer(s). NXP does not accept any liability in this respect.

Limiting values — Stress above one or more limiting values (as defined in the Absolute Maximum Ratings System of IEC 60134) will cause permanent damage to the device. Limiting values are stress ratings only and (proper) operation of the device at these or any other conditions above those given in the Recommended operating conditions section (if present) or the Characteristics sections of this document is not warranted. Constant or repeated exposure to limiting values will permanently and irreversibly affect the quality and reliability of the device.

Terms and conditions of commercial sale — NXP Semiconductors products are sold subject to the general terms and conditions of commercial sale, as published at http://www.nxp.com/profile/terms, unless otherwise agreed in a valid written individual agreement. In case an individual agreement is concluded only the terms and conditions of the respective

PSMN4R0-30YL

All information provided in this document is subject to legal disclaimers.

© NXP B.V. 2011. All rights reserved.

PSMN4R0-30YL

N-channel 30 V 4 m Ω logic level MOSFET in LFPAK

agreement shall apply. NXP Semiconductors hereby expressly objects to applying the customer's general terms and conditions with regard to the purchase of NXP Semiconductors products by customer.

No offer to sell or license — Nothing in this document may be interpreted or construed as an offer to sell products that is open for acceptance or the grant, conveyance or implication of any license under any copyrights, patents or other industrial or intellectual property rights.

Export control — This document as well as the item(s) described herein may be subject to export control regulations. Export might require a prior authorization from national authorities.

Non-automotive qualified products — Unless this data sheet expressly states that this specific NXP Semiconductors product is automotive qualified, the product is not suitable for automotive use. It is neither qualified nor tested in accordance with automotive testing or application requirements. NXP Semiconductors accepts no liability for inclusion and/or use of non-automotive qualified products in automotive equipment or applications.

In the event that customer uses the product for design-in and use in automotive applications to automotive specifications and standards, customer (a) shall use the product without NXP Semiconductors' warranty of the

product for such automotive applications, use and specifications, and (b) whenever customer uses the product for automotive applications beyond NXP Semiconductors' specifications such use shall be solely at customer's own risk, and (c) customer fully indemnifies NXP Semiconductors for any liability, damages or failed product claims resulting from customer design and use of the product for automotive applications beyond NXP Semiconductors' standard warranty and NXP Semiconductors' product specifications.

9.4 Trademarks

Notice: All referenced brands, product names, service names and trademarks are the property of their respective owners.

Adelante, Bitport, Bitsound, CoolFlux, CoReUse, DESFire, EZ-HV, FabKey, GreenChip, HiPerSmart, HITAG, I²C-bus logo, ICODE, I-CODE, ITEC, Labelution, MIFARE, MIFARE Plus, MIFARE Ultralight, MoReUse, QLPAK, Silicon Tuner, SiliconMAX, SmartXA, STARplug, TOPFET, TrenchMOS, TriMedia and UCODE — are trademarks of NXP B.V.

HD Radio and **HD Radio** logo — are trademarks of iBiquity Digital Corporation.

10. Contact information

For more information, please visit: http://www.nxp.com

For sales office addresses, please send an email to: salesaddresses@nxp.com

PSMN4R0-30YL

NXP Semiconductors

N-channel 30 V 4 m Ω logic level MOSFET in LFPAK

11. Contents

1	Product profile	1
1.1	General description	1
1.2	Features and benefits	1
1.3	Applications	1
1.4	Quick reference data	1
2	Pinning information	2
3	Ordering information	2
4	Limiting values	2
5	Thermal characteristics	4
6	Characteristics	5
7	Package outline	.10
8	Revision history	. 11
9	Legal information	.12
9.1	Data sheet status	.12
9.2	Definitions	.12
9.3	Disclaimers	.12
9.4	Trademarks	.13
10	Contact information	12

Please be aware that important notices concerning this document and the product(s) described herein, have been included in section 'Legal information'.

X-ON Electronics

Largest Supplier of Electrical and Electronic Components

Click to view similar products for MOSFET category:

Click to view products by NXP manufacturer:

Other Similar products are found below:

614233C 648584F D2003UK 705463DB MCH6422-TL-E FW231A-TL-E APT5010JFLL NTNS3A92PZT5G IRF100S201 JANTX2N5237

2SK2464-TL-E 2SK3818-DL-E FCA20N60_F109 FDZ595PZ STD6600NT4G FQD4P40TM_AM002 FSS804-TL-E FW217A-TL-2W

APT10050JVFR 2SJ277-DL-E 2SK1691-DL-E 2SK2545(Q,T) D1014UK D2294UK 405094E 423220D MCH6646-TL-E TPCC8103,L1Q(CM IRF3710 367-8430-0972-503 VN1206L 424134F 026935X 051075F SBVS138LT1G 614234A 715780A NTNS3166NZT5G 751625C 873612G IPS70R2K0CEAKMA1 APT8015JVFR APT50M85JVR APT5010JVFR APT12031JFLL APT12040JVR NTE6400 NVC3S5A51PLZT1G JANTX2N6796U JANTX2N6784U